



OMEGA 25 Gb/s link budget analysis

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Introduction and assumptions

Introduction



- This contribution presents a link budget analysis for transmission of 25 Gb/s in extreme automotive temperatures for all the characterized 850 nm VCSELs reported in July and August TF meetings
- Due to the key role of the bias current in the VCSEL reliability, the link budget analysis is parametrized based on I_{BIAS}
- The link budget analysis is based on the link model presented in [perezaranda_OMEGA_01_290920_link_model.pdf](#)

Baseline for link budget analysis

- The following parameters are a small subset of a complete baseline that will be presented in a future meeting
- These parameters are the minimum information of the communications system needed to carry out link budget analysis according to the used link model
 - Data-rate: 25 Gb/s
 - Modulation: NRZ, PAM $M = 2$
 - FEC: RS(544, 522) GF(2^{10})
 - Error correction capability: $t = 11$
 - Code-rate: CR = 0.96
 - Coding-gain: CG = 5.55 dB
 - $F_s = 26.5625$ GBd
 - BER $< 10^{-12}$: SNR_d > 11.07 dB
 - RX equalization: DFE
 - RIL = 0.4 dB (extracted from time-domain simulations of the complete system)

Simulations conditions

- Fiber is OM3, BLP = 2000 MHz·km
- Fiber length = 40 meters
- Number of inline connections: $N_{IC} = 4$
- VCSEL ER = 3 dB
- VCSEL drivers:
 - Current driver w/o FFE
 - Current driver with 3-tap FFE fixed to [-0.125, 1.25, -0.125]
 - Voltage driver w/o FFE
- VCSEL $RIN_{OMA} = -124$ dB/Hz, $BW_n = 20.9$ GHz
- VCSEL I_{BIAS} : from 2 to 6 mA in 0.5 mA steps
- VCSEL temperatures (T_{AMB}) :
 - -40 °C
 - 125 °C
- RX conditions: worst production corner, $T_J = 125$ °C

Channel insertion losses

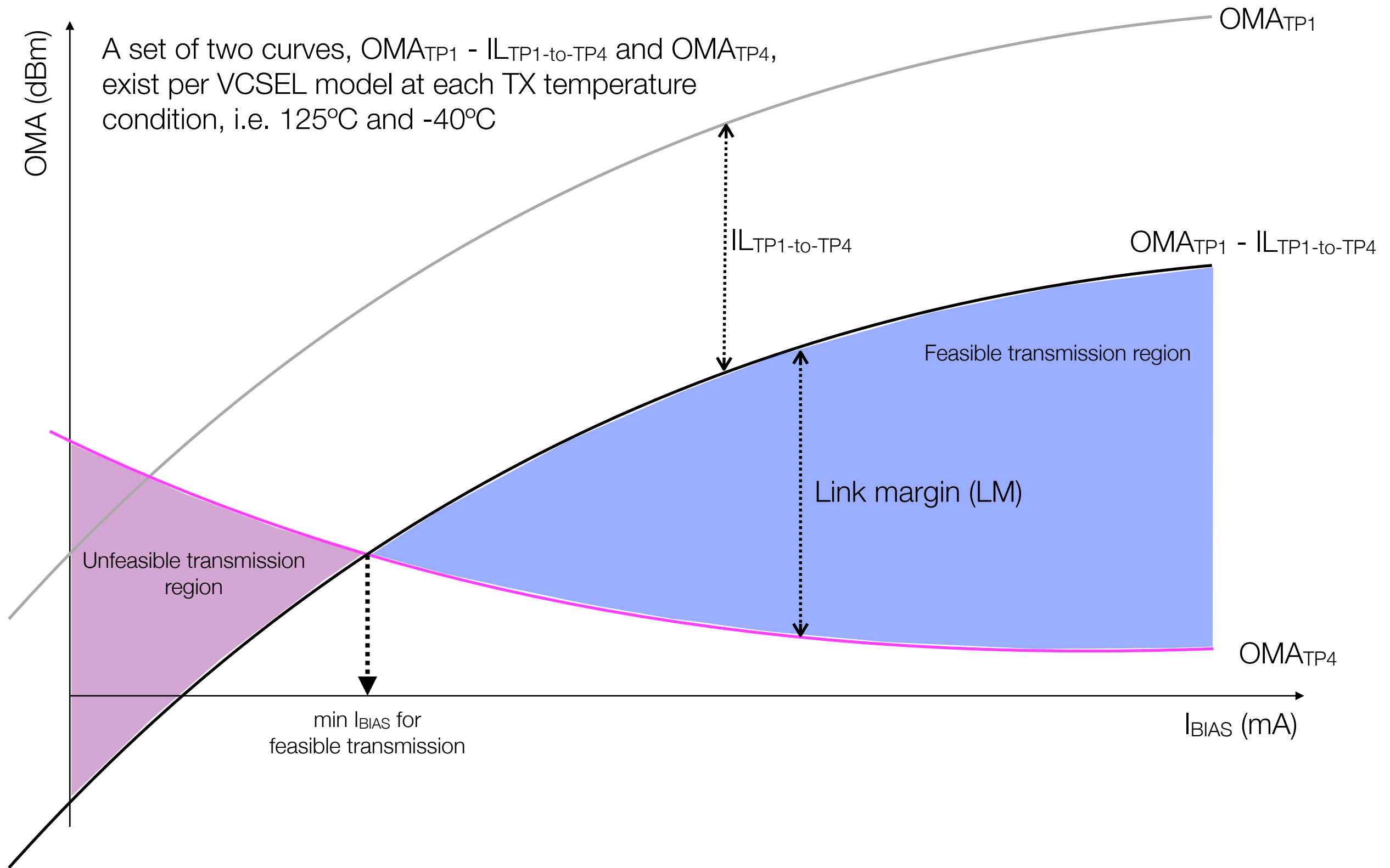


Channel insertion losses

Parameter	Value	
VCSEL SE variation in the same bin (dB)	0.50	A
VCSEL aging (dB)	1.00	B
VCSEL to TP2 max coupling loss (dB)	2.50	C
IL _{TP1-to-TP2} , max (dB)	4.00	D = A + B + C
IL _{TP3-to-TP4} , max (dB)	1.50	E
Insertion loss per inline connection, IL _{IC} max (dB)	1.50	F
Number of inline connections (N _{IC})	4	G
Macrobend insertion loss, max (dB)	0.20	H
Microbend insertion loss, max (dB)	0.00	I
Bending insertion loss, IL _{BEND} max (dB)	0.20	J = H + I
Fiber differential insertion loss (dB/km)	3.00	K
IL _{TP2-to-TP3} , max (dB)	6.32	L = (F × G) + J + (40/1000 × K)
IL _{TP1-to-TP4} , max (dB)	11.82	M = D + E + L

- See perezaranda_OMEGA_01_290920_link_model.pdf slides 5 and 26 for the definition of the test points, insertion losses and link budget

How to do the link budget analysis?

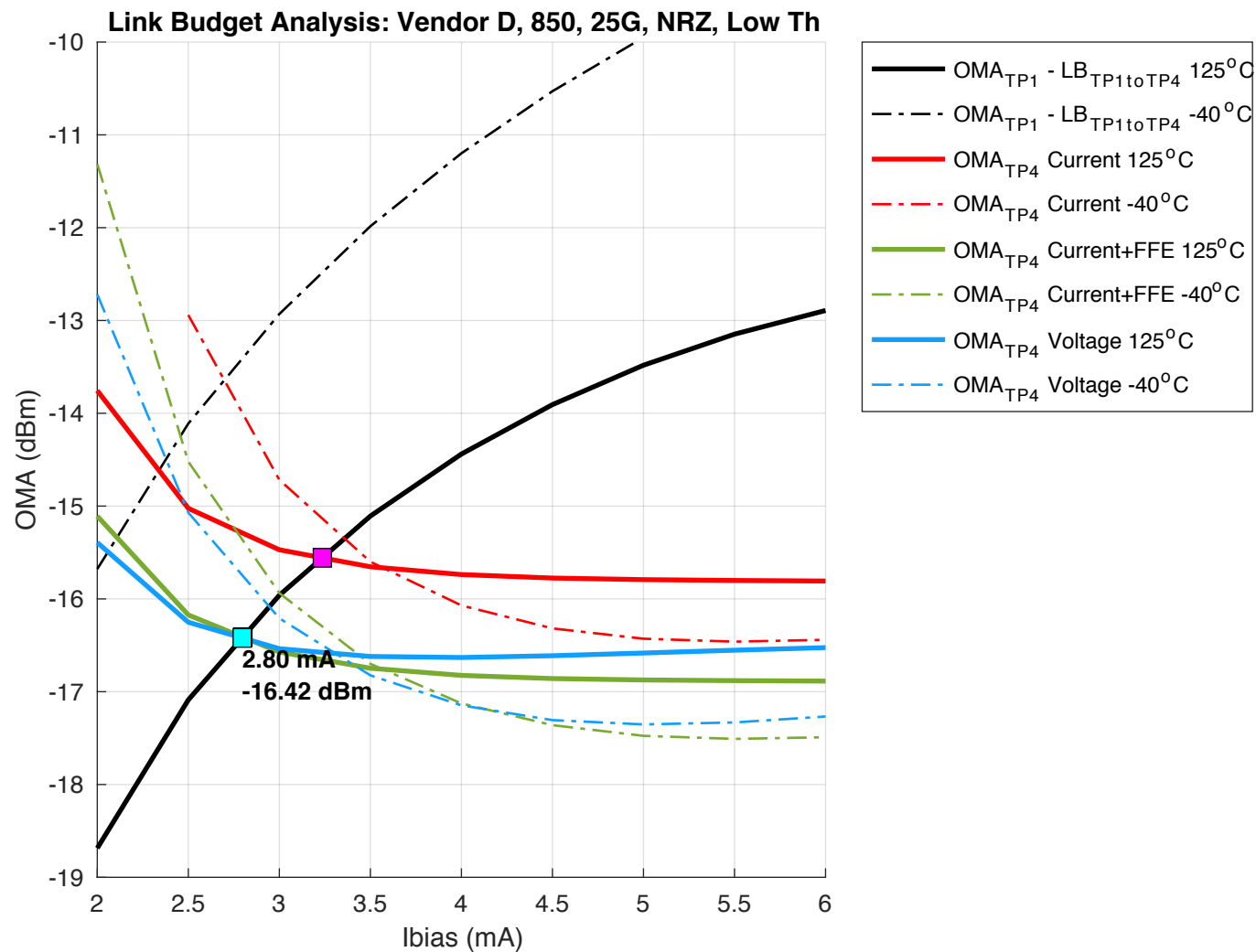




25 Gb/s link budget results

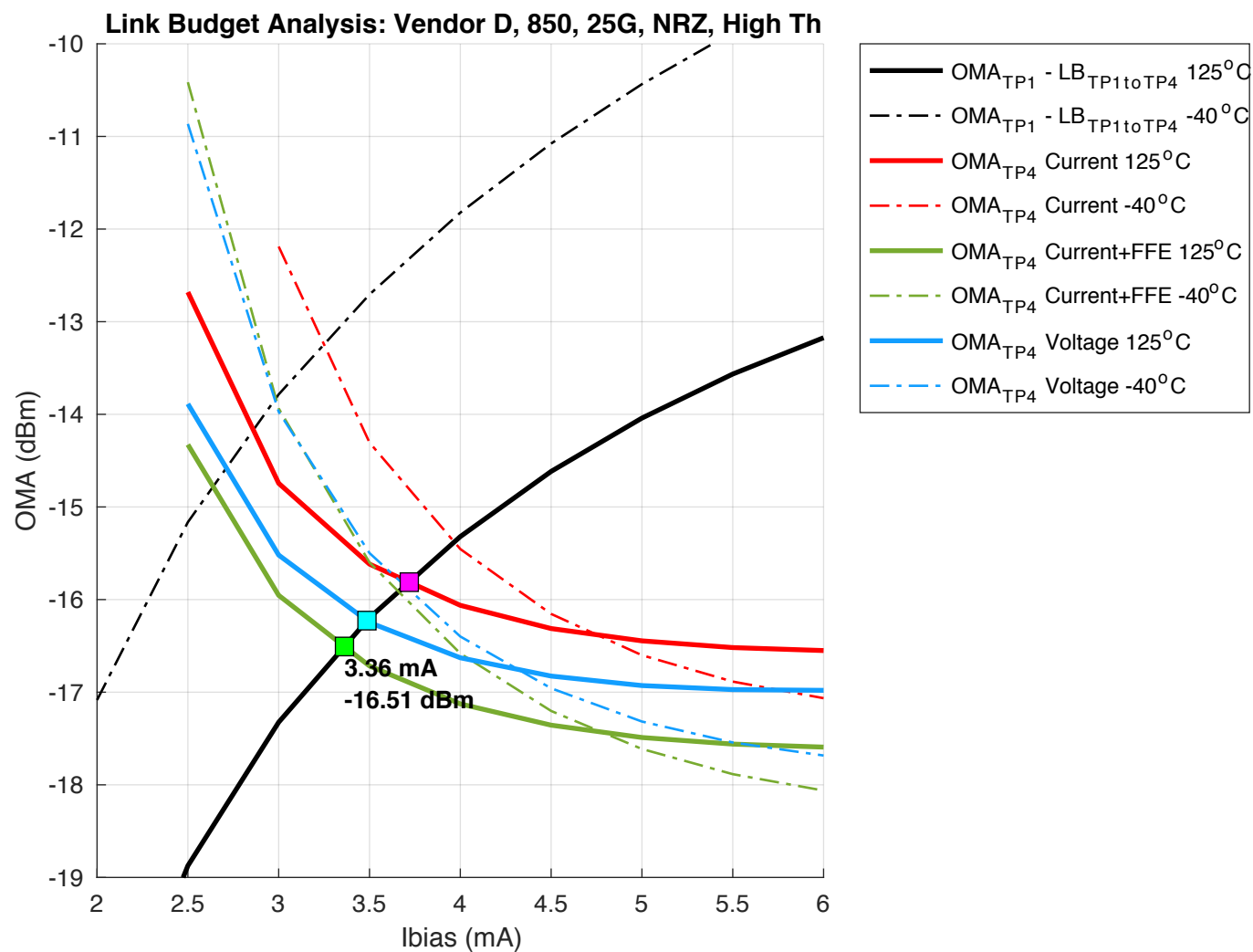
Minimum I_{BIAS} for 125°C operation and feasibility for -40°C

Vendor D, 850 nm, 25G, NRZ, low threshold



- Note: the RX implementation is common for all the simulations. Worst production corner and $T_J = 125^\circ\text{C}$ conditions
- $T_{\text{VCSEL}} = 125^\circ\text{C}$:
 - Squares used to indicate the crossing points of OMA_{TP4} sensitivity curves of different VCSEL driving options with the OMA_{TP1} - I_{LTP1-to-TP4} curve. They represent the min I_{BIAS} for feasible transmission in each case.
 - Current driver w/ FFE and voltage driver improve by 1 dB the OMA_{TP4} sensitivity achieved with current driver w/o FFE
 - 25 Gb/s transmission is feasible with very low VCSEL I_{BIAS} operation, which helps to improve the reliability
 - I_{BIAS} = 2.80 mA, OMA_{TP4} = -16.42 dBm
- $T_{\text{VCSEL}} = -40^\circ\text{C}$:
 - 25 Gb/s transmission is feasible
 - OMA_{TP4} sensitivity is worse for low I_{BIAS}, however, it is better for higher ones
 - OMA_{TP1} is higher in low temperatures for the same I_{BIAS}
 - Additionally, high I_{BIAS} can be used w/o affecting reliability in low temperatures

Vendor D, 850 nm, 25G, NRZ, high threshold



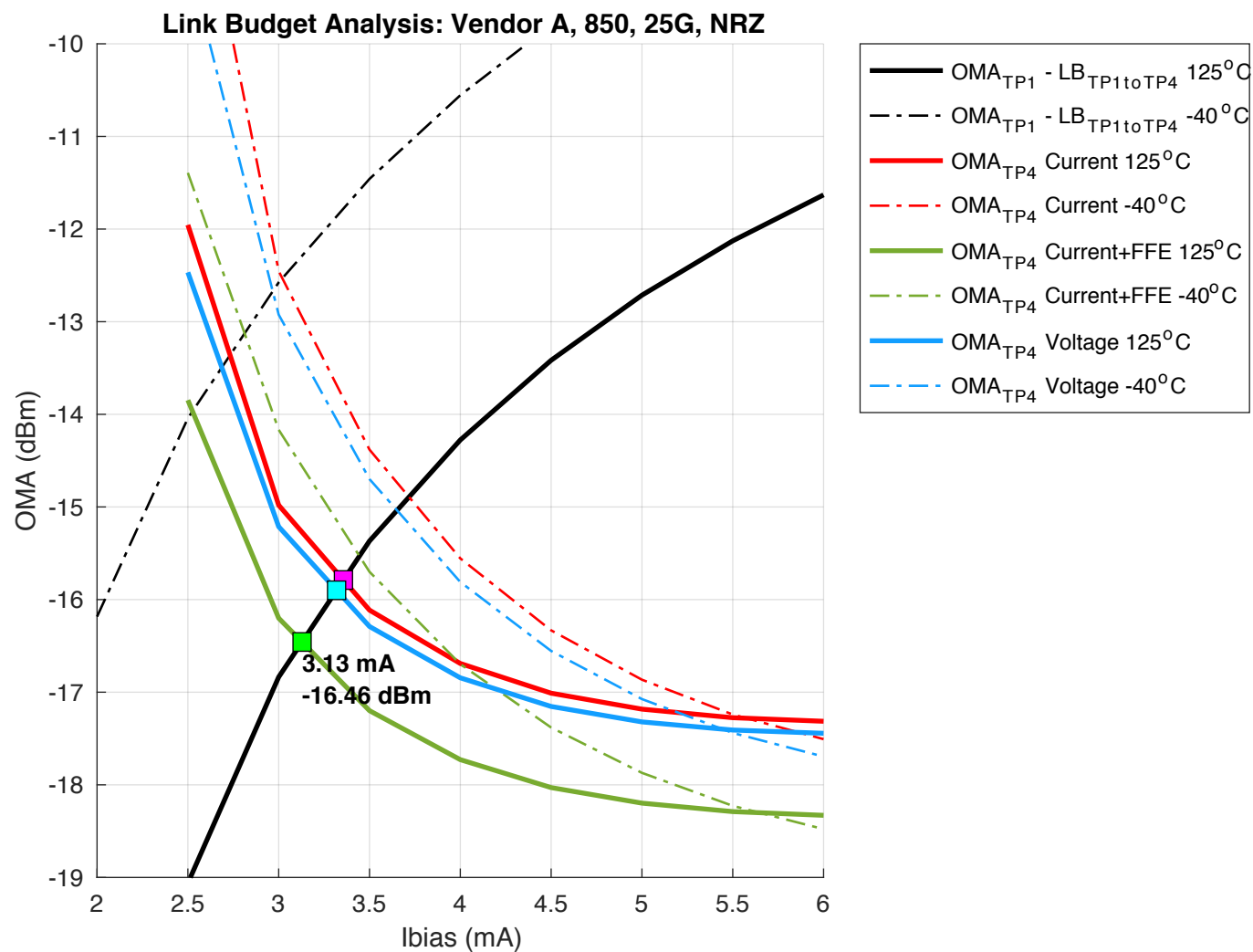
- $T_{VCSEL} = 125^{\circ}\text{C}$:

- Current driver w/ FFE improves by 1 dB the OMA_{TP4} sensitivity achieved with current driver w/o FFE. Voltage driver is not so effective
- 25 Gb/s transmission is feasible with low VCSEL I_{BIAS} operation, which helps to improve the reliability
- Higher threshold corners have larger oxide aperture, so I_{BIAS} can be increased for the same current density, i.e. reliability
- I_{BIAS} = 3.36 mA, OMA_{TP4} = -16.51 dBm

- $T_{VCSEL} = -40^{\circ}\text{C}$:

- 25 Gb/s transmission is feasible
- OMA_{TP4} sensitivity is worse for low I_{BIAS}, however, it is better for higher ones
- OMA_{TP1} is higher in low temperatures for the same I_{BIAS}
- Additionally, high I_{BIAS} can be used w/o affecting reliability in low temperatures

Vendor A, 850 nm, 25G, NRZ



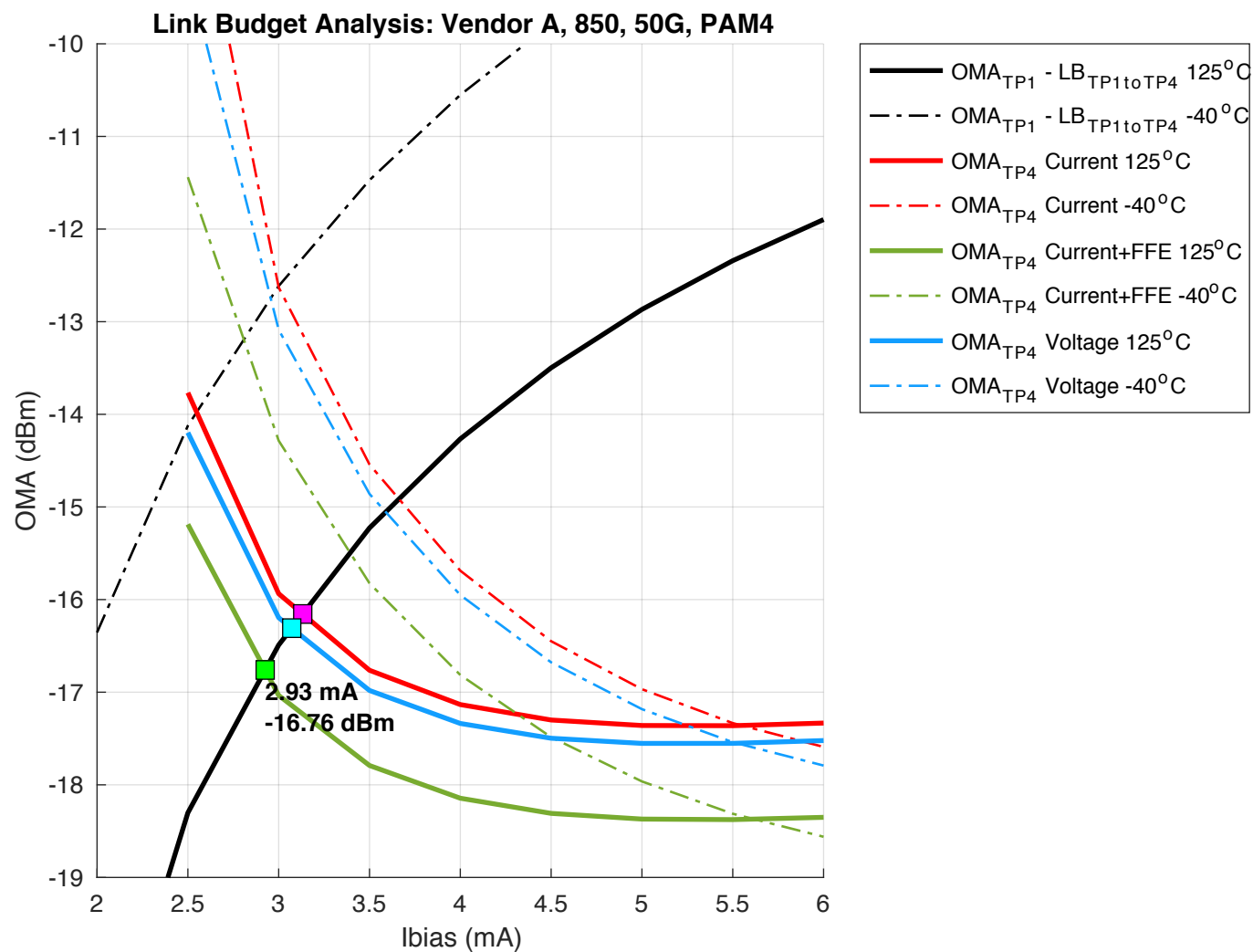
- $T_{VCSEL} = 125^{\circ}\text{C}$:

- Current driver w/ FFE improves by 1 dB the OMA_{TP4} sensitivity achieved with current driver w/o FFE. Voltage driver is not effective
- 25 Gb/s transmission is feasible with low VCSEL I_{BIAS} operation, which helps to improve the reliability
- I_{BIAS} = 3.13 mA, OMA_{TP4} = -16.46 dBm

- $T_{VCSEL} = -40^{\circ}\text{C}$:

- 25 Gb/s transmission is feasible
- OMA_{TP4} sensitivity is worse for low I_{BIAS}, however, it is better for higher ones
- OMA_{TP1} is higher in low temperatures for the same I_{BIAS}
- Additionally, high I_{BIAS} can be used w/o affecting reliability in low temperatures

Vendor A, 850 nm, 50G, PAM4



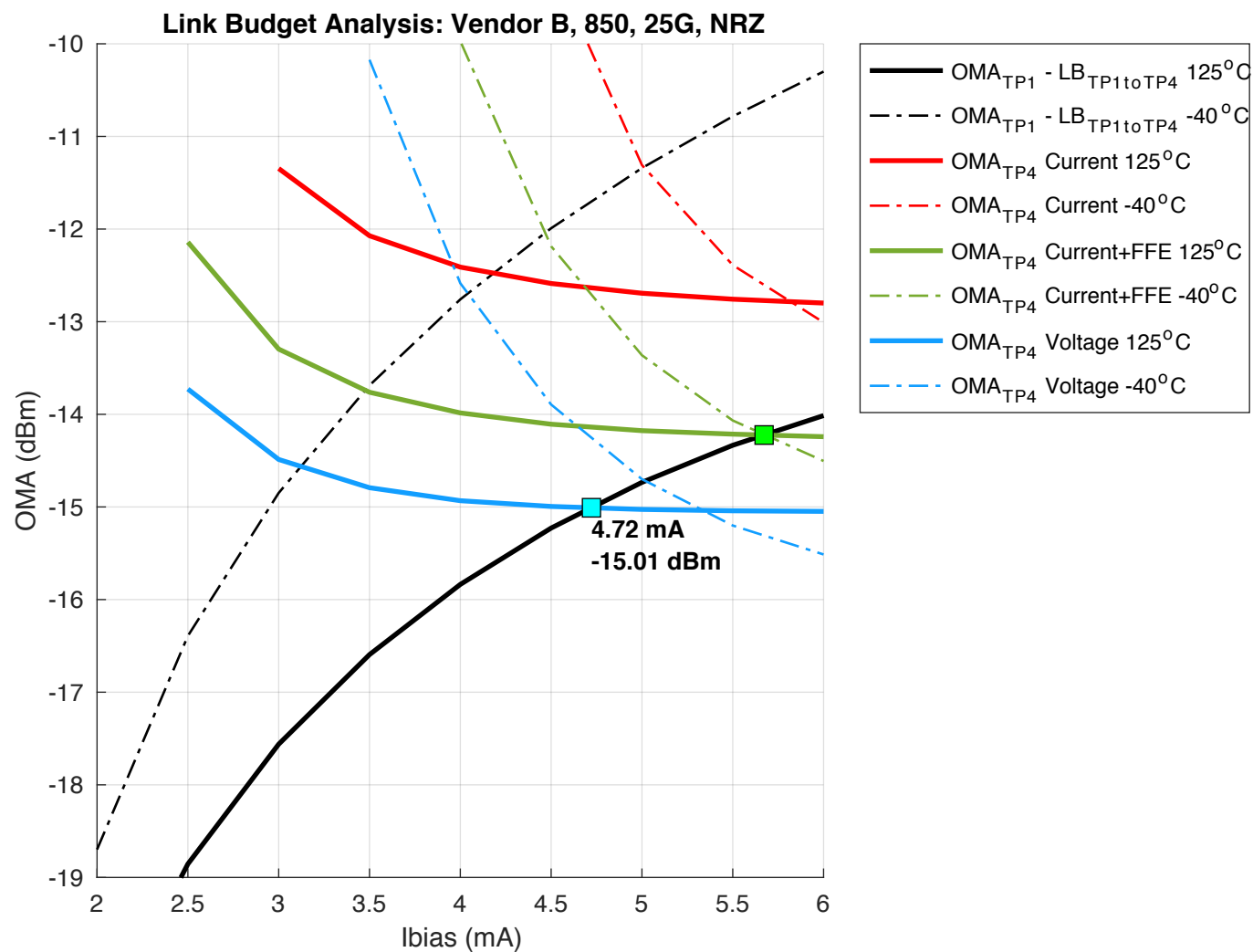
- $T_{VCSEL} = 125^{\circ}\text{C}$:

- Current driver w/ FFE improves by 1 dB the OMA_{TP4} sensitivity achieved with current driver w/o FFE. Voltage driver is not effective
- 25 Gb/s transmission is feasible with very low VCSEL I_{BIAS} operation, which helps to improve the reliability
- I_{BIAS} = 2.93 mA, OMA_{TP4} = -16.76 dBm

- $T_{VCSEL} = -40^{\circ}\text{C}$:

- 25 Gb/s transmission is feasible
- OMA_{TP4} sensitivity is worse for low I_{BIAS}, however, it is better for higher ones
- OMA_{TP1} is higher in low temperatures for the same I_{BIAS}
- Additionally, high I_{BIAS} can be used w/o affecting reliability in low temperatures

Vendor B, 850 nm, 25G, NRZ



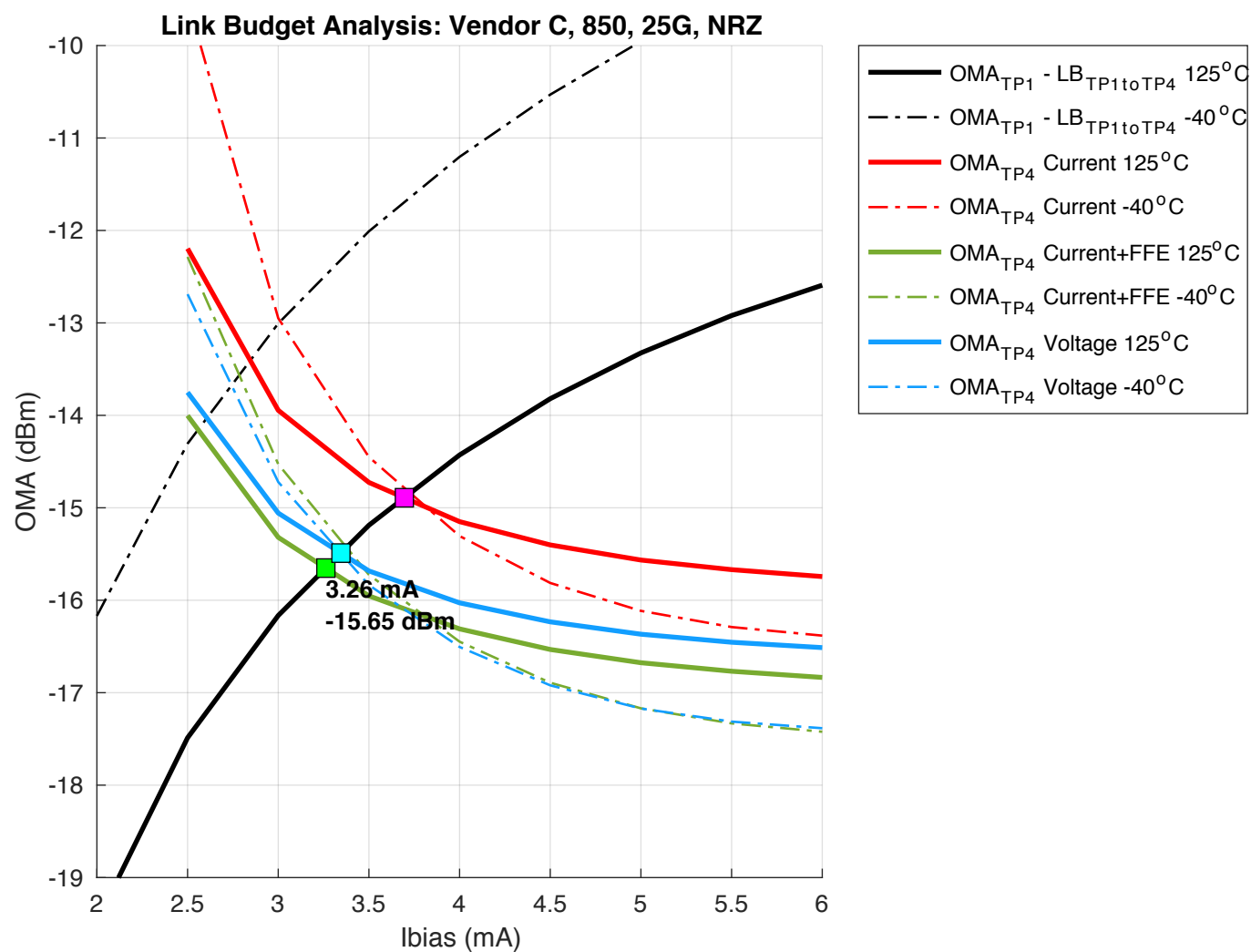
- $T_{VCSEL} = 125^{\circ}C$:

- Current driver w/ FFE improves by 1.5 dB the OMA_{TP4} sensitivity achieved with current driver w/o FFE. Voltage driver improves by 2.3 dB the OMA_{TP4} sensitivity
- Nevertheless, this VCSEL requires of high I_{BIAS} to make 25 Gb/s transmission feasible, which may impact its reliability
- Achieved OMA_{TP4} sensitivity is worse by ~1.5 dB compared with other VCSELs
- I_{BIAS} = 4.72 mA, OMA_{TP4} = -15.01 dBm

- $T_{VCSEL} = -40^{\circ}C$:

- 25 Gb/s transmission is feasible
- OMA_{TP4} sensitivity is worse for low I_{BIAS}, however, it is better for higher ones
- OMA_{TP1} is higher in low temperatures for the same I_{BIAS}
- Additionally, high I_{BIAS} can be used w/o affecting reliability in low temperatures

Vendor C, 850 nm, 25G, NRZ



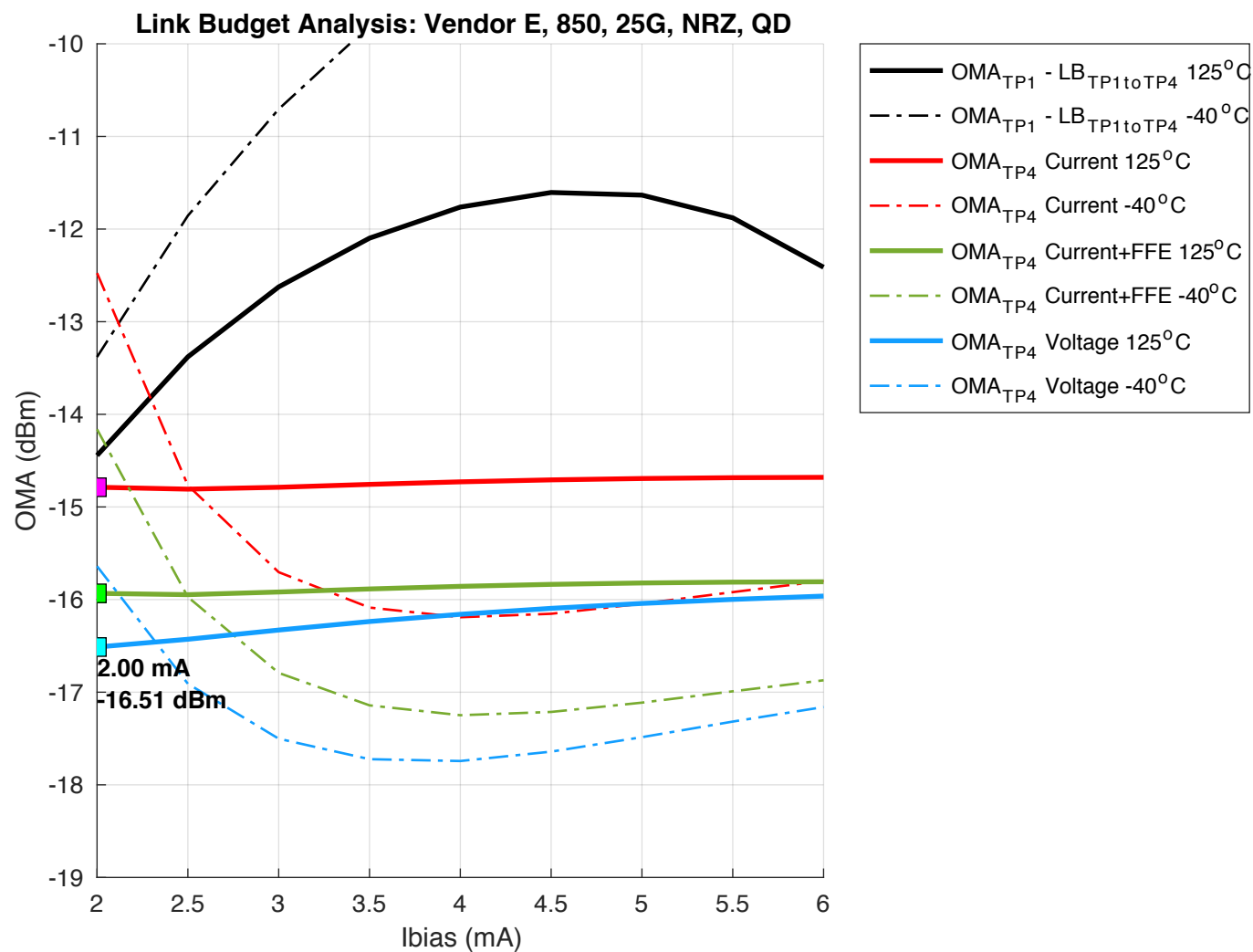
- $T_{VCSEL} = 125^{\circ}\text{C}$:

- Current driver w/ FFE improves by 1 dB the OMA_{TP4} sensitivity achieved with current driver w/o FFE. Voltage driver is a little less effective
- 25 Gb/s transmission is feasible with low VCSEL current operation, which helps to improve the reliability
- Achieved OMA_{TP4} sensitivity is ~1 dB worse compared with other VCSELs
- $I_{BIAS} = 3.26 \text{ mA}$, OMA_{TP4} = -15.65 dBm

- $T_{VCSEL} = -40^{\circ}\text{C}$:

- 25 Gb/s transmission is feasible
- OMA_{TP4} sensitivity is worse for low I_{BIAS} , however, it is better for higher ones
- OMA_{TP1} is higher in low temperatures for the same I_{BIAS}
- Additionally, high I_{BIAS} can be used w/o affecting reliability in low temperatures

Vendor E, 850 nm, 25G, NRZ, QD



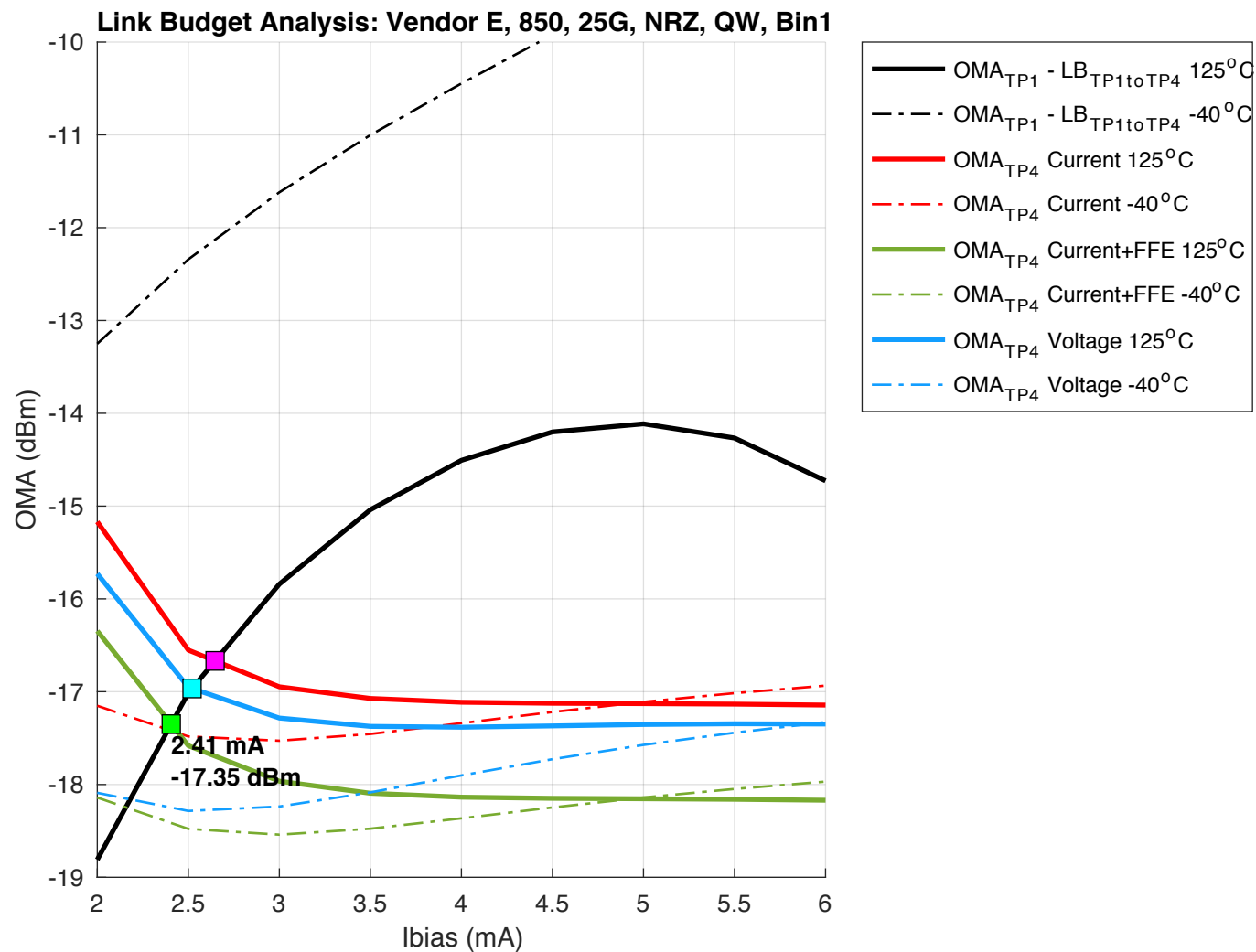
- $T_{VCSEL} = 125^{\circ}C$:

- Current driver w/ FFE improves by 1.1 dB the OMA_{TP4} sensitivity achieved with current driver w/o FFE. Voltage driver improves by 1.7 dB the OMA_{TP4} sensitivity
- 25 Gb/s transmission is feasible with very low VCSEL I_{BIAS} operation, which helps to improve the reliability
- OMA_{TP1} thermal rollover at 4.5 mA may indicate that oxide aperture is smaller compared to other VCSELs, and current density is therefore higher, providing higher bandwidth with lower I_{BIAS}
- I_{BIAS} = 2.00 mA, OMA_{TP4} = -16.51 dBm

- $T_{VCSEL} = -40^{\circ}C$:

- 25 Gb/s transmission is feasible
- OMA_{TP4} sensitivity is worse for low I_{BIAS}, however, it is better for higher ones
- OMA_{TP1} is higher in low temperatures for the same I_{BIAS}
- Additionally, high I_{BIAS} can be used w/o affecting reliability in low temperatures

Vendor E, 850 nm, 25G, NRZ, QW, Bin1



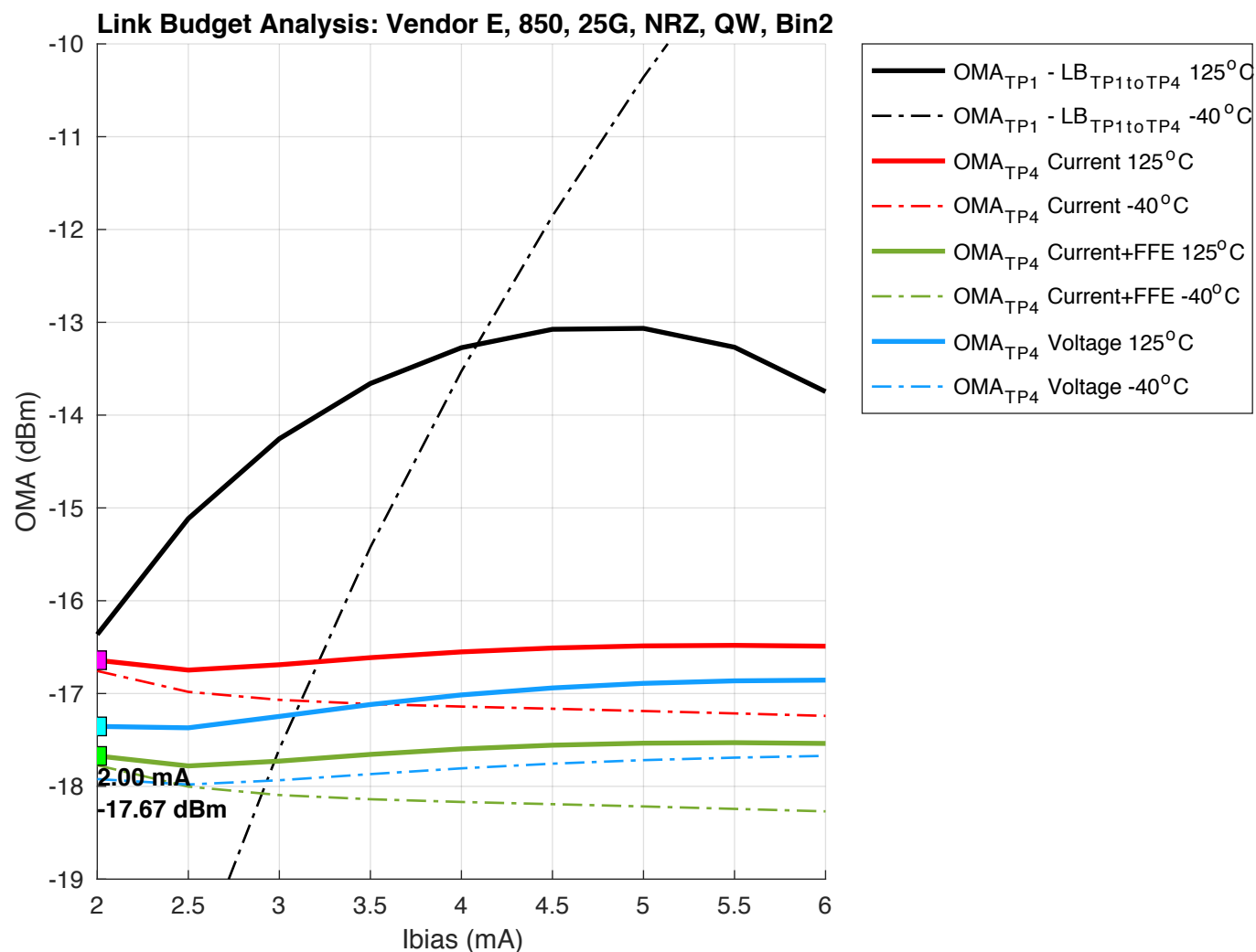
- $T_{VCSEL} = 125^{\circ}C$:

- Current driver w/ FFE improves by 1 dB the OMA_{TP4} sensitivity achieved with current driver w/o FFE. Voltage driver is not effective in improving sensitivity
- 25 Gb/s transmission is feasible with very low VCSEL I_{BIAS} operation, which helps to improve the reliability
- OMA_{TP1} thermal rollover at 4.5 mA may indicate that oxide aperture is smaller compared to other VCSELs, and current density is therefore higher, providing higher bandwidth with lower I_{BIAS}
- Very low OMA_{TP4} sensitivity achievable
- I_{BIAS} = 2.41 mA, OMA_{TP4} = -17.35 dBm

- $T_{VCSEL} = -40^{\circ}C$:

- 25 Gb/s transmission is feasible
- OMA_{TP4} sensitivity is almost constant with I_{BIAS}
- OMA_{TP1} is higher in low temperatures for the same I_{BIAS}
- Additionally, high I_{BIAS} can be used w/o affecting reliability in low temperatures

Vendor E, 850 nm, 25G, NRZ, QW, Bin1



- $T_{VCSEL} = 125^{\circ}C$:

- Current driver w/ FFE improves by 1 dB the OMA_{TP4} sensitivity achieved with current driver w/o FFE. Voltage driver is not so effective in improving sensitivity
- 25 Gb/s transmission is feasible with very low VCSEL I_{BIAS} operation, which helps to improve the reliability
- OMA_{TP1} thermal rollover at 4.5 mA may indicate that oxide aperture is smaller compared to other VCSELs, and current density is therefore higher, providing higher bandwidth with lower I_{BIAS}
- Very low OMA_{TP4} sensitivity achievable
- $I_{BIAS} = 2.00$ mA, $OMA_{TP4} = -17.67$ dBm

- $T_{VCSEL} = -40^{\circ}C$:

- 25 Gb/s transmission is feasible
- OMA_{TP4} sensitivity is almost constant with I_{BIAS}
- OMA_{TP1} is very dependent of I_{BIAS} , being very low for $I_{BIAS} < 3.5$ mA
- However, high I_{BIAS} can be used w/o affecting reliability in low temperatures



25 Gb/s link budget results

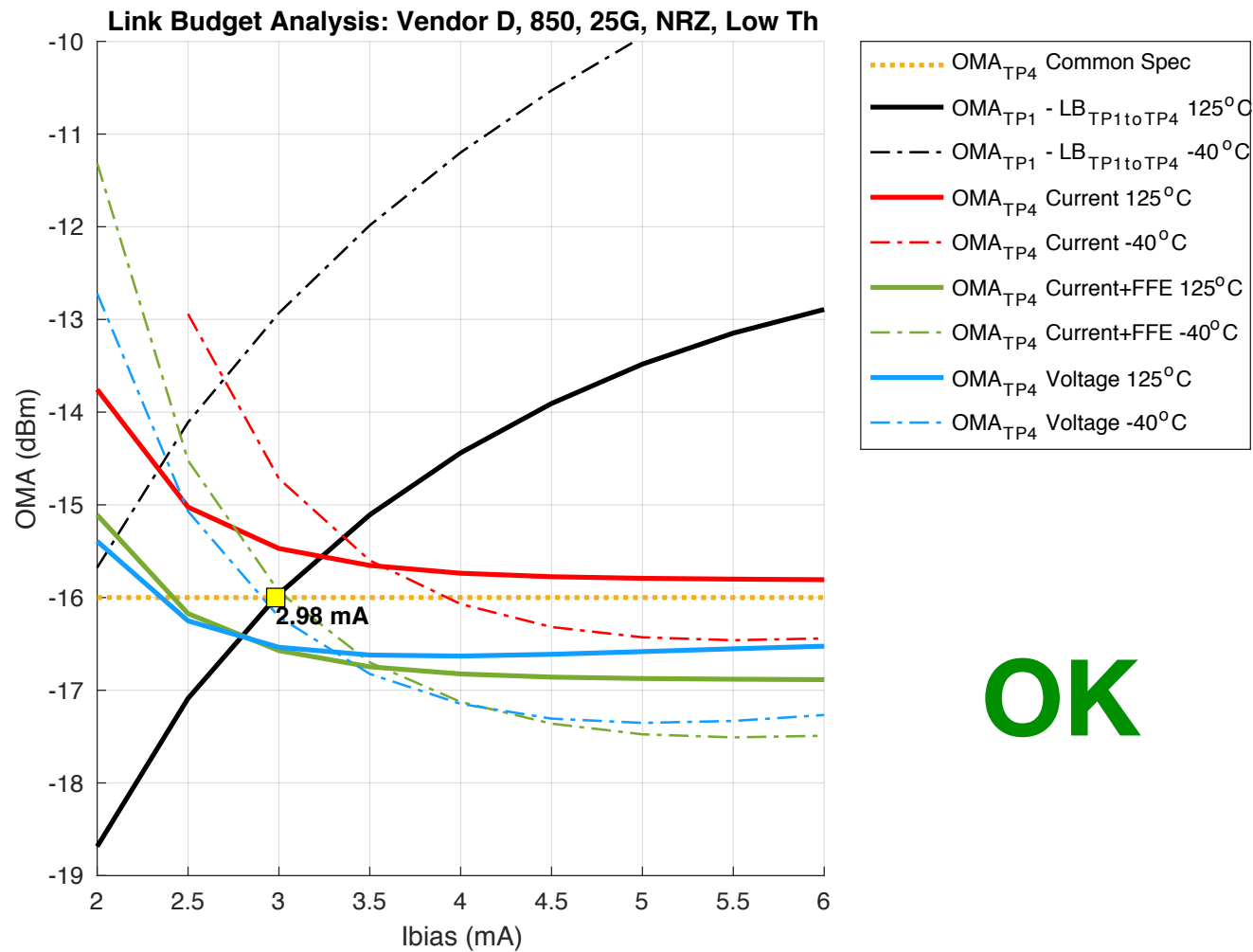
Towards a common receiver sensitivity

Is it possible a common receiver sensitivity?

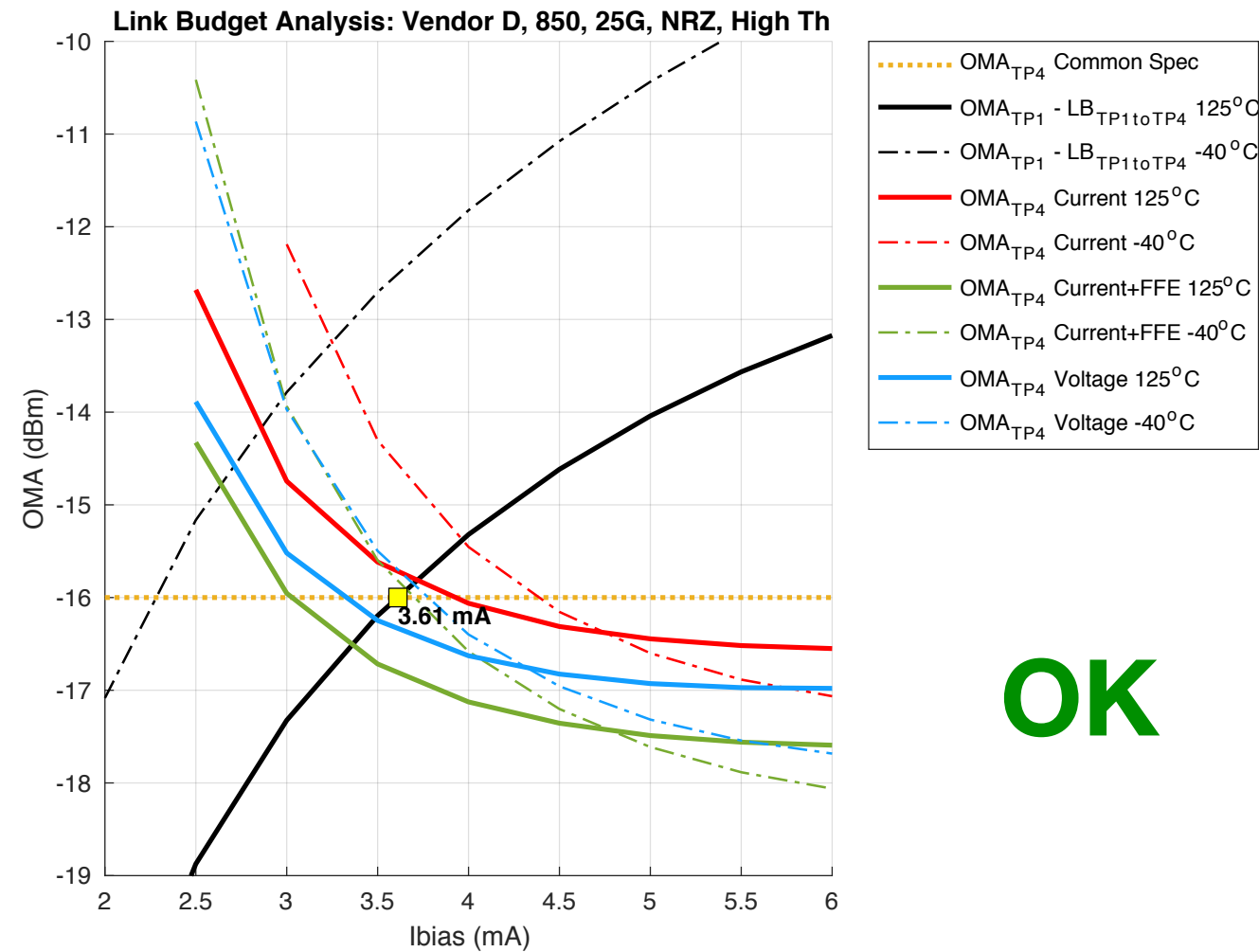


- The presented results showed that for $T_{VCSEL} = 125\text{ }^{\circ}\text{C}$ different VCSELs in minimum I_{BIAS} operation produce different sensitivity levels in the receiver (OMA_{TP4}), as well as different transmit optical power levels (OMA_{TP1})
- If a VCSEL that produces worse RX sensitivity can compensate the budget with higher transmit optical power, then the link is feasible
- On the other hand, a VCSEL with lower transmit power may produce better RX sensitivity, making the link also feasible
- Questions:
 - Q1: Is there a common receiver sensitivity level for low VCSEL I_{BIAS} operation (i.e. high reliability) valid for the most part of the evaluated VCSELs?
 - Q2: Is the same common receiver sensitivity level valid for -40°C
- The answer is YES, as it will be demonstrated in the following slides
- Disclaimer:
 - The sensitivity levels in this contribution assumes an specific RX implementation
 - Criteria for testing the RX sensitivity is needed to be defined by the TF to guarantee interoperability. It is not in the scope of this contribution

Common RX sensitivity: $OMA_{TP4} = -16$ dBm



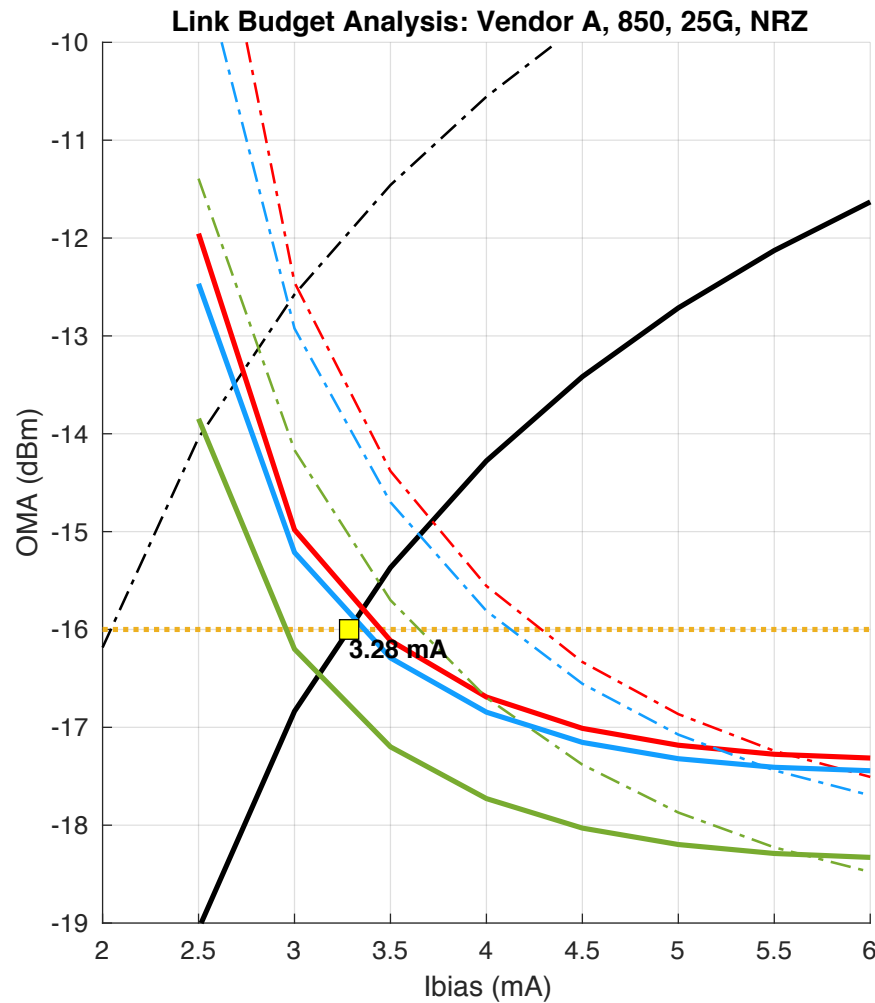
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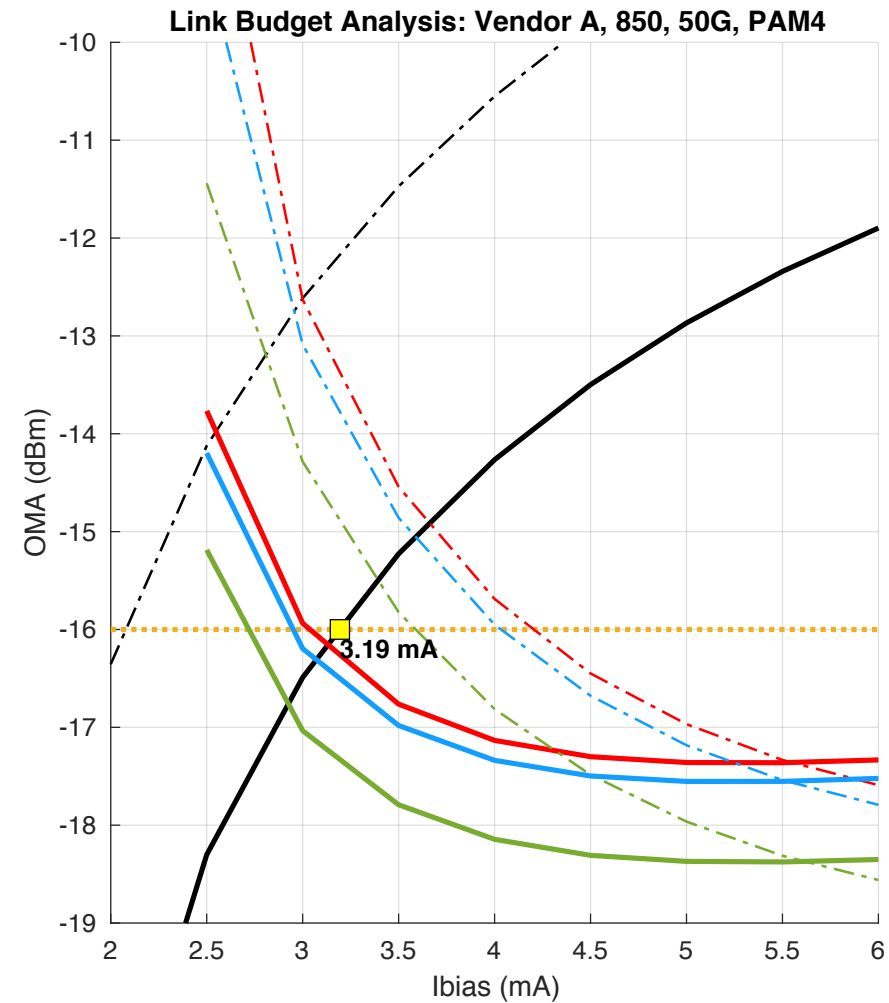
- OMA_{TP4} common level needs to be higher than or equal to OMA_{TP4} sensitivity curve obtained for at least one of the VCSEL driving options, in both -40°C and 125°C in order to consider a particular VCSEL part is compatible with such a common specification
- OMA_{TP4} common level needs to be lower than or equal to OMA_{TP1} - IL_{TP1-to-TP4} for feasible transmission, per definition of slide 7
- The yellow square is used to show the crossing point of OMA_{TP4} common level with the curve OMA_{TP1} - IL_{TP1-to-TP4} at 125°C indicating the resultant minimum I_{BIAS} for feasible transmission at 125°C that meets such common level. If no intersection exists, then the yellow square just indicates the minimum I_{BIAS} over the OMA_{TP1} - IL_{TP1-to-TP4} curve
- In -40°C, high bias current can be used w/o affecting reliability

Common RX sensitivity: $OMA_{TP4} = -16$ dBm



- OMA_{TP4} Common Spec
- $OMA_{TP1} - LB_{TP1toTP4}$ 125°C
- - - $OMA_{TP1} - LB_{TP1toTP4}$ -40°C
- OMA_{TP4} Current 125°C
- - - OMA_{TP4} Current -40°C
- OMA_{TP4} Current+FFE 125°C
- - - OMA_{TP4} Current+FFE -40°C
- OMA_{TP4} Voltage 125°C
- - - OMA_{TP4} Voltage -40°C

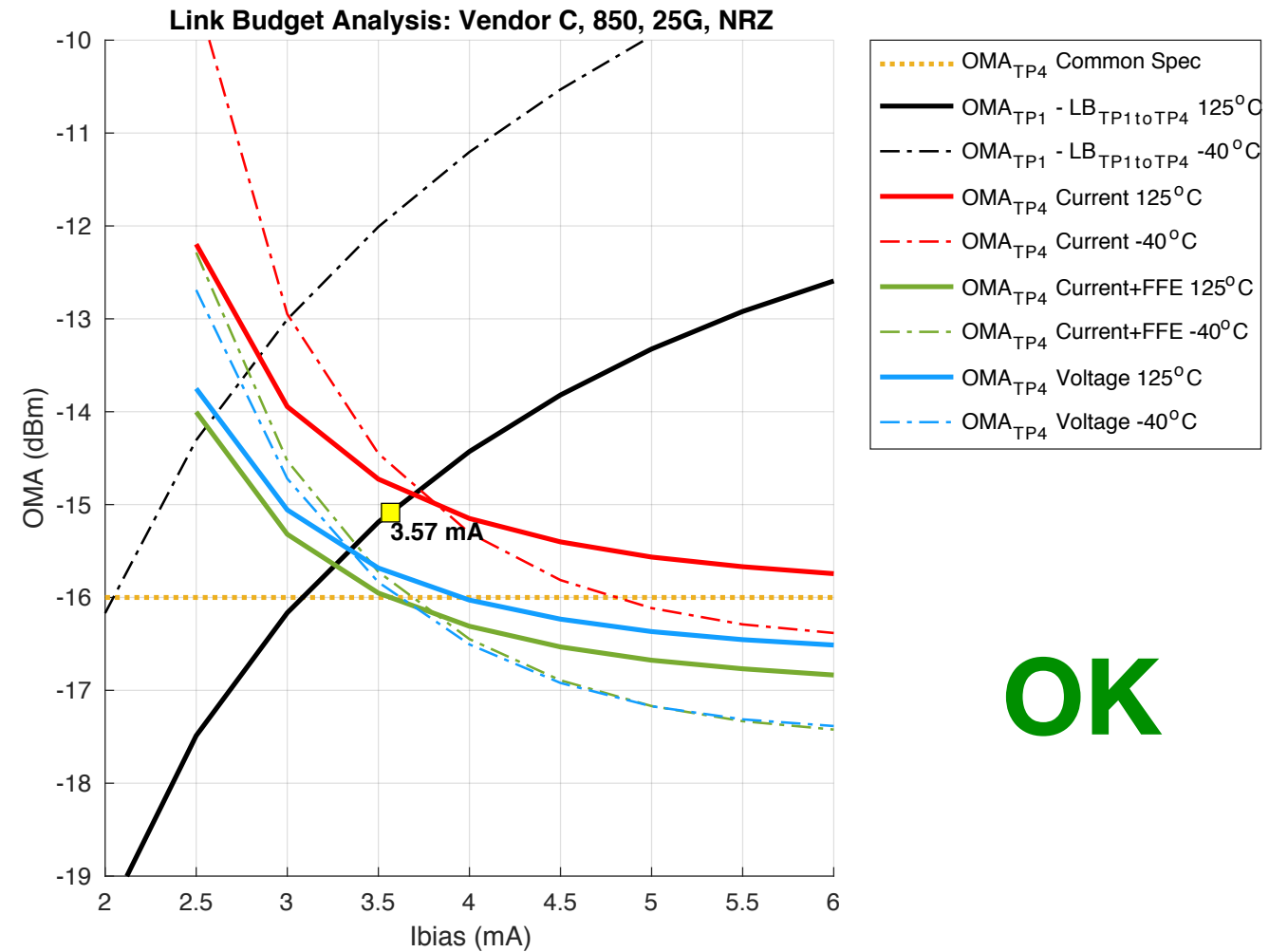
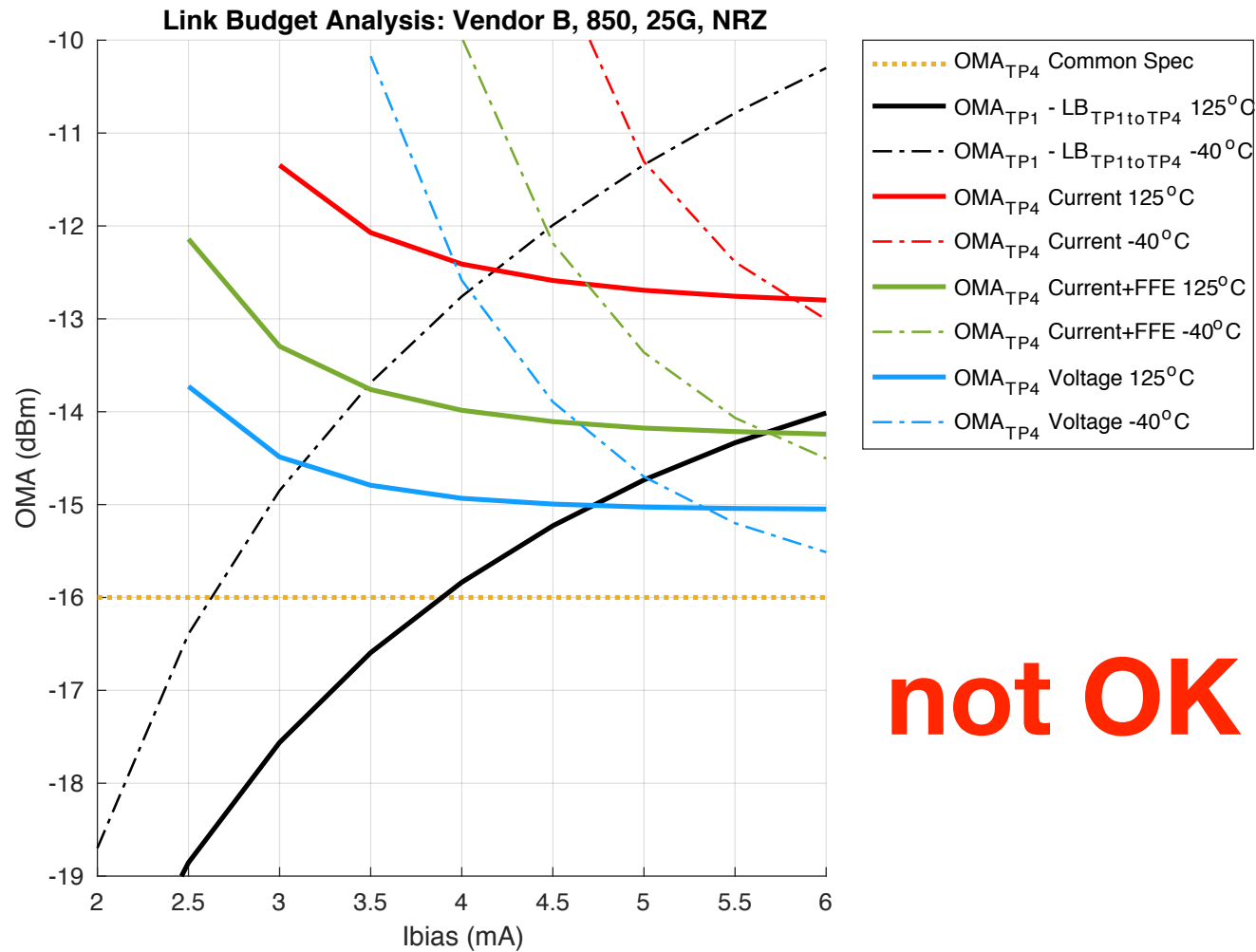
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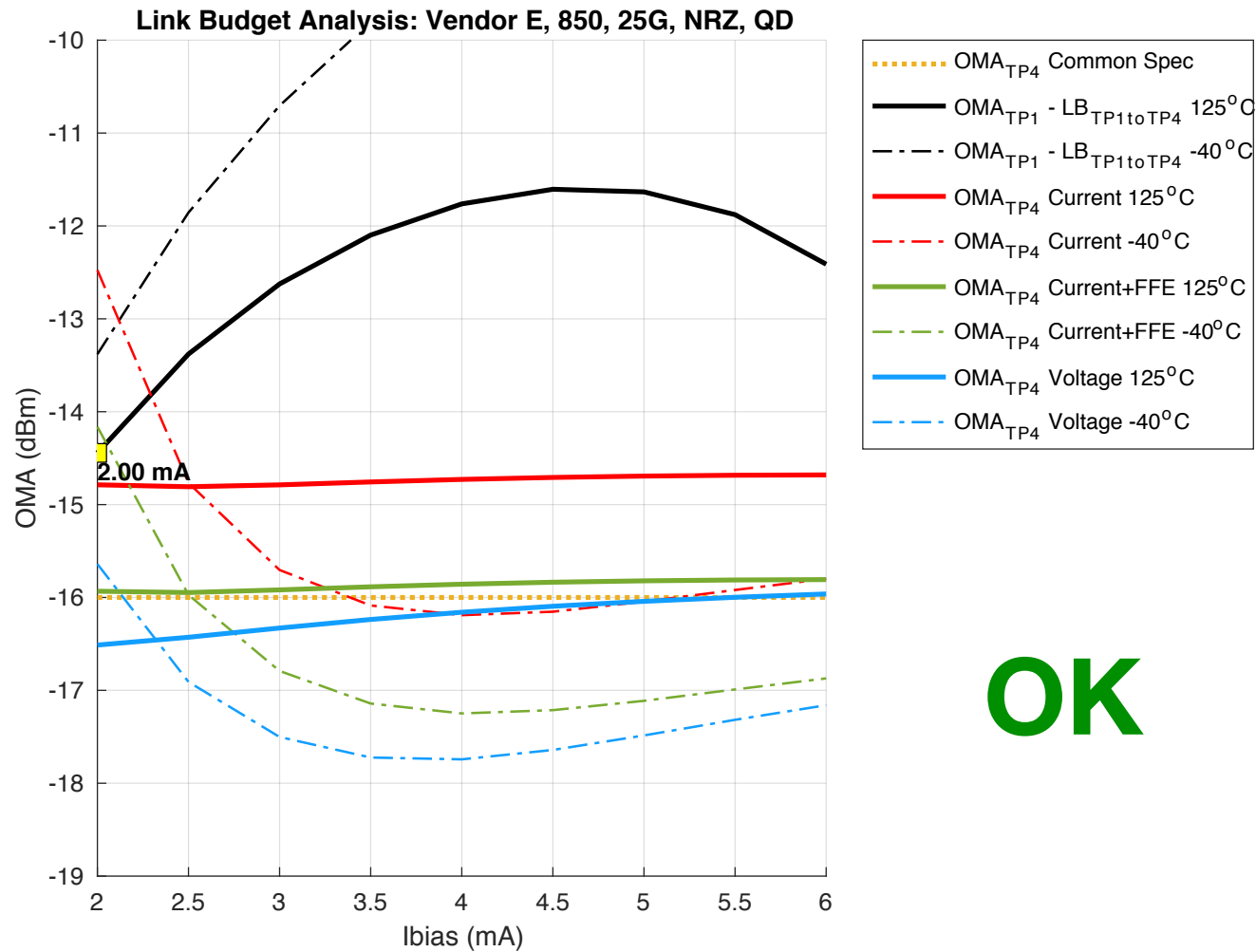
- OMA_{TP4} Common Spec
- $OMA_{TP1} - LB_{TP1toTP4}$ 125°C
- - - $OMA_{TP1} - LB_{TP1toTP4}$ -40°C
- OMA_{TP4} Current 125°C
- - - OMA_{TP4} Current -40°C
- OMA_{TP4} Current+FFE 125°C
- - - OMA_{TP4} Current+FFE -40°C
- OMA_{TP4} Voltage 125°C
- - - OMA_{TP4} Voltage -40°C

OK

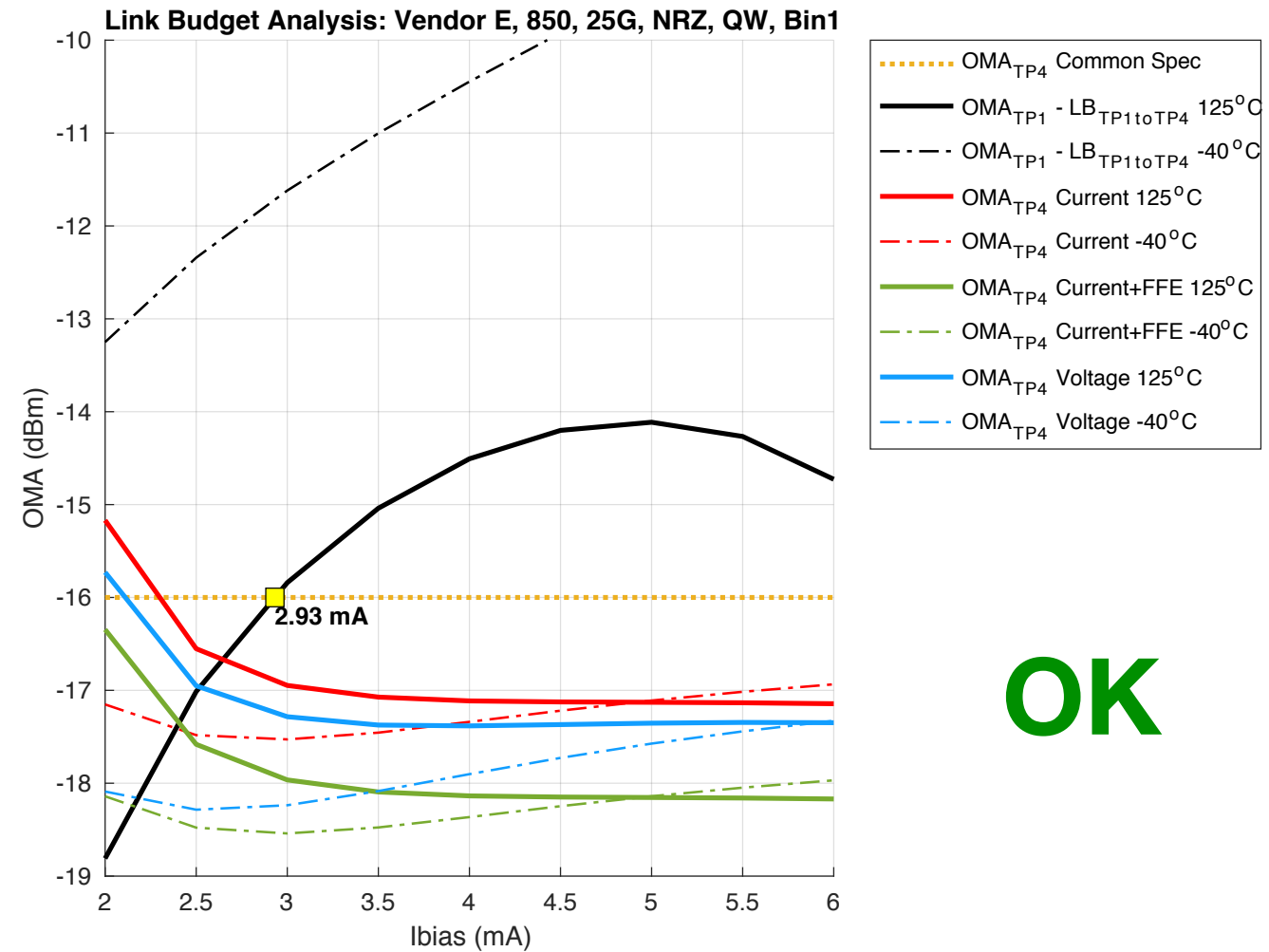
Common RX sensitivity: $OMA_{TP4} = -16$ dBm



Common RX sensitivity: $OMA_{TP4} = -16$ dBm

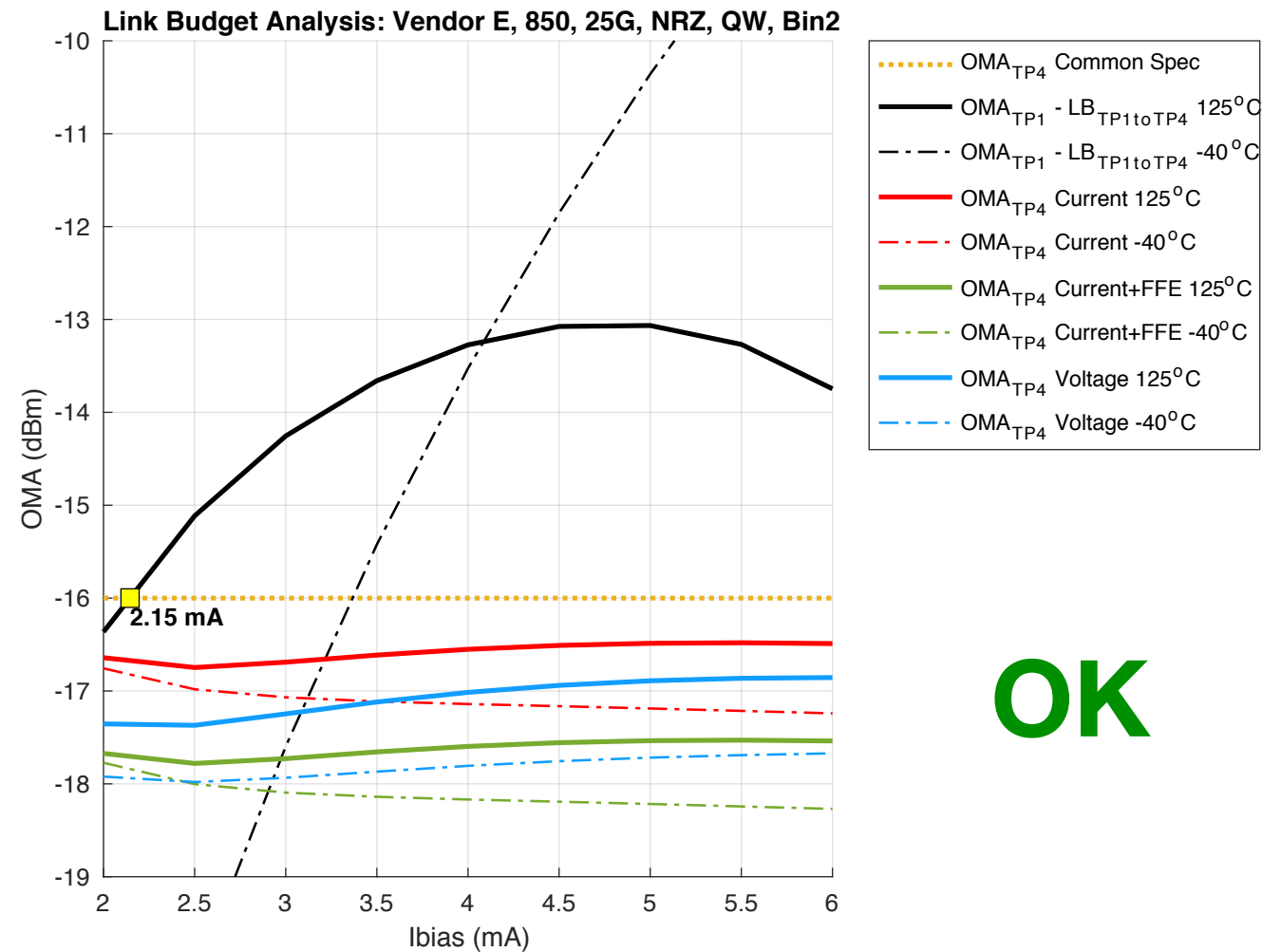


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OK

Common RX sensitivity: $OMA_{TP4} = -16$ dBm



OK

Conclusions



- 25 Gb/s operation with low VCSEL bias current has been demonstrated feasible for almost all evaluated VCSELs, in temperatures of 125°C and -40°C
- Wear-out reliability data provided by VCSEL vendors is needed to confirm that bias currents found for each VCSEL are consistent to achieve automotive lifetime reliability requirements
- Link budget for longer wavelength VCSELs have not been reported because assembly of the tested 990nm device presented much larger thermal resistance than expected in real use, making the characterization pessimistic for 125°C and optimistic for -40°C (see [perezaranda_OMEGA_05a_0720_VendorD_VCSEL.pdf](#))
 - Once solved this issue, link budget analysis for longer wavelength VCSELs will be presented



Thank you!